

# JIS

JAPANESE  
INDUSTRIAL  
STANDARD

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Japanese Standards Association

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(JEMIMA/JSA)

## Circuit Testers

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ICS 17.220.20

**Descriptors :** circuits, circuit elements, testing, test equipment, electrical measuring instruments, electrical measurement, electrical testing

**Reference number :** JIS C 1202 : 2000 (E)

## Foreword

This translation has been made based on the original Japanese Industrial Standard revised by the Minister of International Trade and Industry through deliberations at the Japanese Industrial Standards Committee, as the result of proposal for revision of Japanese Industrial Standard submitted by the Japan Electric Measuring Instruments Manufacturers Association (**JEMIMA**)/the Japanese Standards Association (**JSA**) with the draft being attached, based on the provision of Article 12 Clause 1 of the Industrial Standardization Law. Consequently **JIS C 1202 : 1986** is replaced with this Standard.

In this revision items relating to safety and to digital circuit tester are added and conformity with **JIS C 1102 Electrical indicating instruments** which has been revised for international conformity is planned.

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In the event of any doubts arising as to the contents,  
the original JIS is to be the final authority.

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## Circuit testers

**1 Scope** This Japanese Industrial Standard specifies analog circuit testers, digital circuit testers which are designed to measure electrical quantities of three or more kinds from among d.c. voltage, d.c. current, a.c. voltage, a.c. current and resistances and testing leads as the standard accessory. However, circuit testers which utilizes an external power supply for the measurement of such quantities, those designed to measure a voltage exceeding 1 200 V, probes for high voltage measurement and analog circuit testers which accommodate amplifiers are excluded.

**Remarks :** A circuit tester may provide additional scales (or functions) for low frequency output, temperature, closed-circuit voltage of dry cell, load voltage, load current, d.c. amplification of transistor, etc. by utilizing its functions for measuring voltages, currents or resistances.

**2 Normative references** The following standards contain provisions which, through reference in this Standard, constitute provisions of this Standard. If the indication of the year of coming into effect is given to these referred standards, only the edition of indicated year constitutes the provision of this Standard but the revision and amendment made thereafter are not applied.

JIS C 0040 : 1995	<i>Basic environmental testing procedures Part 2 : Tests Test Fc and guidance : Vibration (sinusoidal)</i>
JIS C 0041 : 1995	<i>Basic environmental testing procedures Part 2 : Tests Test Ea and guidance : Shock</i>
JIS C 0066 : 1993	<i>Methods of test for the determination of the flammability of solid electrical insulating materials when exposed to an igniting source</i>
JIS C 0301 : 1990	<i>Graphical symbols for electrical apparatus</i>
JIS C 1010·1 : 1998	<i>Safety requirements for electrical equipment for measurement, control, and laboratory use—Part 1 : General requirements</i>
JIS C 1010·2·31 : 1998	<i>Safety requirements for electrical equipment for measurement, control, and laboratory use—Part 2-31 : Particular requirements for hand-held probe assemblies for electrical measurement and test</i>
JIS C 1102 : 1997	<i>Direct acting indicating analogue electrical measuring instruments and their accessories</i>
JIS C 5111 : 1995	<i>General rules of fixed plastic film capacitors for use in electronic equipment</i>